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Quantitative Investigation of Cu/In thin Films Deposited onto SiO2 by Electron Beam Evaporation

Thin In/Cu films were grown on a SiO2 substrate. Both In and Cu layers were grown by e-beam evaporation. The films were characterized with X-ray Diffraction (XRD) and Auger Electron Spectroscopy (AES). The In diffused into the Cu layer during evaporation and formed two intermetallic Cu11In9 and CuIn2 phases.

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